STP5N120

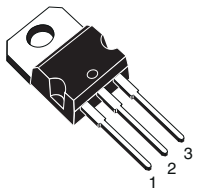
N-channel 1200V - 2.8Ω - 4.4A - TO-220
Zener - protected SuperMESH™ Power MOSFET

TARGET SPECIFICATION

Features

Type	V_{DSS}	$R_{DS(on)}$	I_D	P_W
STP5N120	1200V	< 3.5 Ω	4.4A	160W

- 100% avalanche tested
- Extremely high dv/dt capability
- ESD improved capability
- New high voltage benchmark
- Gate charge minimized

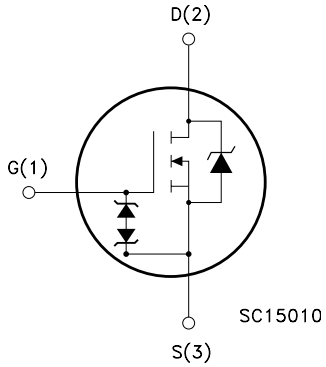


TO-220

Description

The SuperMESH™ series is obtained through an extreme optimization of ST's well established strip-based PowerMESH™ layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST full range of high voltage Power MOSFETs.

Internal schematic diagram



Application

- Switching application

Order code

Part number	Marking	Package	Packaging
STP5N120	5N120	TO-220	Tube

Contents

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage (V_{GS}=0)	1200	V
V_{GS}	Gate-source voltage	± 30	V
I_D	Drain current (continuous) at T_C = 25°C	4.4	A
I_D	Drain current (continuous) at T_C = 100°C	2.772	A
I_{DM} (1)	Drain current (pulsed)	17.6	A
	Derating factor	1.28	W/°C
P_{TOT}	Total dissipation at T_C = 25°C	160	W
$V_{ESD(G-S)}$	Gate source ESD (HBM-C = 100pF, R= 1.5KΩ)	3000	V
dv/dt (2)	Peak diode recovery voltage slope	4.5	V/ns
T_j T_{stg}	Operating junction temperature Storage temperature	-55 to 150	°C

1. Pulse width limited by safe operating area
2. I_{SD} ≤4.4A, di/dt ≤200A/µs, V_{DD} ≤80% $V_{(BR)DSS}$

Table 2. Thermal data

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case max	0.78	°C/W
Rthj-amb (1)	Thermal resistance junction-amb max	62.5	°C/W
T_l	Maximum lead temperature for soldering purpose	300	°C

1. When mounted on 1inch² FR-4 board, 2 oz Cu

Table 3. Avalanche characteristics

Symbol	Parameter	Max value	Unit
I_{AS}	Avalanche current, repetitive or not-repetitive (pulse width limited by Tj max)	4.4	A
E_{AS}	Single pulse avalanche energy (starting Tj=25°C, I_D=I_{AS}, V_{DD}= 50V)	Tbd	mJ

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	I_D = 1mA, V_{GS}= 0	1200			V
I_{DSS}	Zero gate voltage drain current (V_{GS} = 0)	V_{DS} = Max rating, V_{DS} = Max rating,Tc=125°C			1 50	µA µA
I_{GSS}	Gate body leakage current (V_{DS} = 0)	V_{GS} = ± 30V			±10	µA
$V_{GS(th)}$	Gate threshold voltage	V_{DS}= V_{GS}, I_D = 100µA	3	3.75	4.5	V
$R_{DS(on)}$	Static drain-source on resistance	V_{GS}= 10V, I_D= 2.3A		2.8	3.5	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
g_{fs} (1)	Forward transconductance	V_{DS} = 15V, I_D = 2.3A		Tbd		S
C_{iss} C_{oss} C_{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V_{DS} =25V, f=1MHz, V_{GS}=0		120 115 25		pF pF pF
$C_{oss\ eq.}$ (2)	Equivalent output capacitance	V_{GS} = 0V, V_{DS} = 0V to 800V		50		pF
R_G	Intrinsic gate resistance	f = 1MHz open drain		Tbd		Ω
Q_g Q_{gs} Q_{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD}=960V, I_D = 4.4A V_{GS} =10V *(see Figure 2)*		55 8 22		nC nC nC

1. Pulsed: pulse duration=300µs, duty cycle 1.5%
2. Coss eq. is defined as a constant equivalent capacitance giving the same charging time as Coss when V_{DS} increases from 0 to 80% V_{DSS}

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	Turn-on delay time Rise time Turn-off delay time Fall time	V_{DD} = 600V, I_D = 2.2A, R_G=4.7Ω, V_{GS}=10V *(see Figure 4)*		Tbd Tbd Tbd Tbd		ns ns ns ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
I_{SD} I_{SDM}	Source-drain current Source-drain current (pulsed)				4.4 17.6	mA A
V_{SD} (1)	Forward on voltage	I_{SD}= 4.4A, V_{GS}=0			1.6	V
t_{rr} Q_{rr} I_{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD}= 4.4A, V_{DD}=100V di/dt = 50A/µs,Tj=25°C *(see Figure 3)*		Tbd Tbd Tbd		ns µC A
t_{rr} Q_{rr} I_{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD}= 4.4A,V_{DD}=100V di/dt=50A/µs,Tj=150°C *(see Figure 3)*		Tbd Tbd Tbd		ns µC A

1. Pulsed: pulse duration = 300µs, duty cycle 1.5%

Table 8. Gate-source zener diode

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
BV_{GSO} (1)	Gate-source breakdown voltage	Igs ± 1mA, (open drain)	30			V

1. The built-in-back zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated zener diodes thus avoid the usage of external components.

3 Test circuit

Figure 1. Switching times test circuit for resistive load

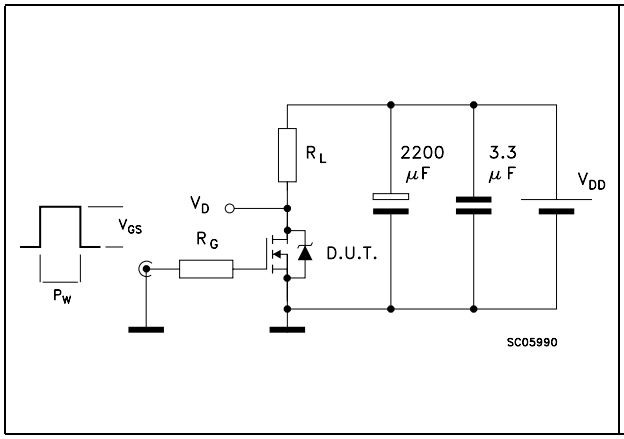


Figure 2. Gate charge test circuit

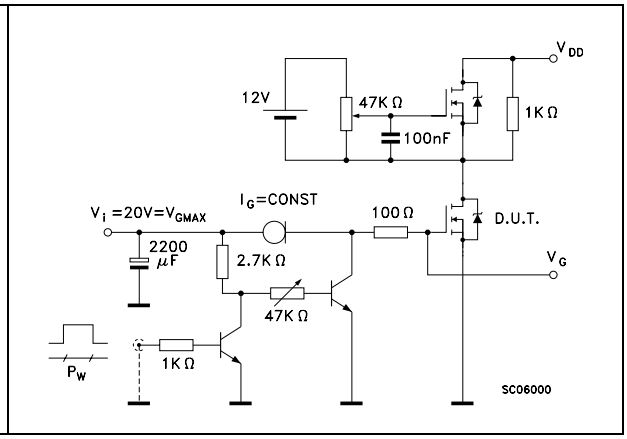


Figure 3. Test circuit for inductive load switching and diode recovery times

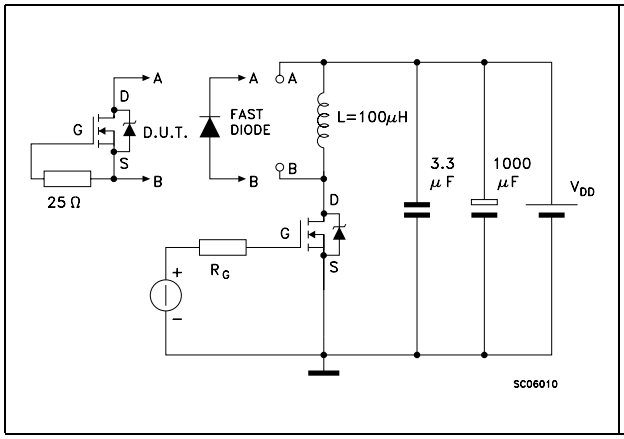


Figure 4. Unclamped inductive load test circuit

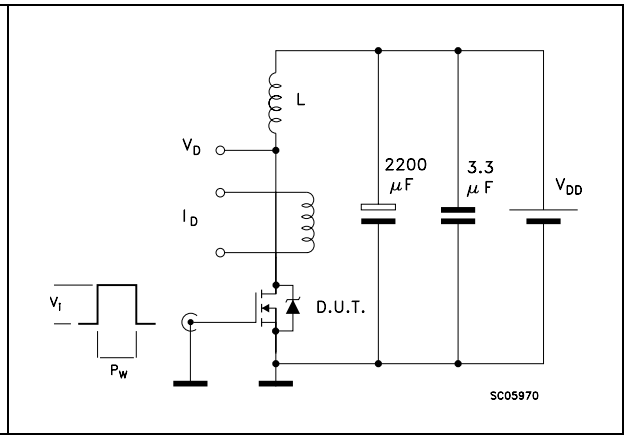


Figure 5. Unclamped inductive waveform

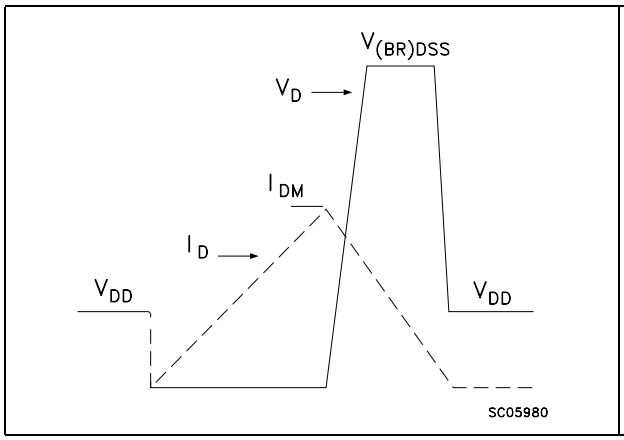
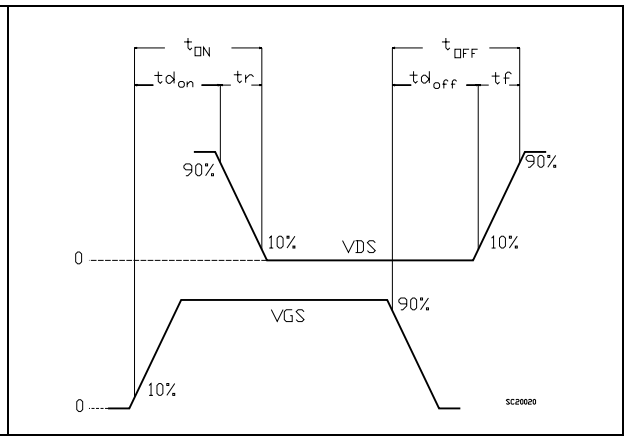


Figure 6. Switching time waveform

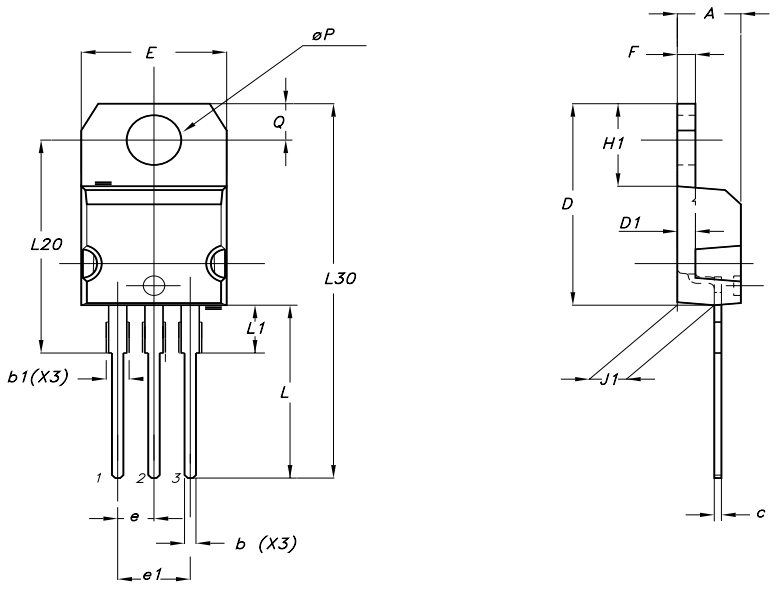


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: *www.st.com*

TO-220 mechanical data

Dim	mm			inch		
	Min	Typ	Max	Min	Typ	Max
A	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.14		1.70	0.044		0.066
c	0.49		0.70	0.019		0.027
D	15.25		15.75	0.6		0.62
D1		1.27			0.050	
E	10		10.40	0.393		0.409
e	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.051
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
∅P	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116



5 Revision history

Table 9. Revision history

Date	Revision	Changes
21-May-2007	1	First release

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